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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani
Title: Inspection System For Integrated Applications
Application No.: 10/659,556 Filing Date: September 9, 2003
Examiner: Unknown Group Art Unit: 2877
Docket No.: TNCR.207US1 Conf. No.: 3091

Certificate of Mailing Under 37 CFR 1.8

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Signature

Mail Stop Amendment
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INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited

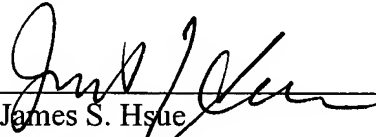
Attorney Docket No.:
TNCR.207US1

Application No.:
10/659,556

document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

Respectfully submitted,


James S. Hsue
Reg. No. 29,545

6/9/04
Date

PARSONS HSUE & DE RUNTZ LLP
655 Montgomery Street, Suite 1800
San Francisco, CA 94111
(415) 318-1160 (main)
(415) 318-1162 (direct)
(415) 693-0194 (fax)

U.S. Department of Commerce, Patent and Trademark		Atty. Docket No.	Application No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		TNCR.207US1	10/659,556
		Applicant(s)	Conf. No.
		Vaez-Iravani et al.	3091
		Filing Date	Group
		September 9, 2003	2877

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	1	4,314,763	2/1982	Steigmeier et al.			
	2	4,378,159	3/1983	Galbraith			
	3	4,391,524	7/1983	Steigmeier et al.			
	4	4,423,331	12/1983	Koizumi et al.			
	5	4,479,714	10/1984	Lehrer			
	6	4,508,450	4/1985	Ohshima et al.			
	7	4,523,841	6/1985	Brunsting et al.			
	8	4,526,468	7/1985	Steigmeier et al.			
	9	4,598,997	7/1986	Steigmeier et al.			
	10	4,735,504	4/1998	Tycko			
	11	4,744,663	5/1988	Hamashima et al.			
	12	4,794,265	12/1988	Quackenbos et al.			
	13	4,893,932	1/1990	Knoffenberg			
	14	4,898,471	2/1990	Stonestrom et al.			
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	16	5,076,692	12/1991	Neukermans et al.			
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	21	5,315,609	5/1994	Tanaka et al.			
	22	5,377,001	12/1994	Malin et al.			
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	29	5,650,614	7/1997	Yasutake et al.			
	30	5,798,829	8/1998	Vaez-Iravani et al.			

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				September 9, 2003			2877	
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	31	5,798,831	8/1998	Hagiwara				
	32	5,864,394	1/1999	Jordan, III et al.				
	33	6,104,945	8/2000	Modell et al.				
	34	6,201,601	3/2001	Vaez-Iravani et al.				
	35	6,271,916	8/2001	Marxer et al.				
	36	6,538,730	3/2003	Vaez-Iravani et al.				
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	37	PCTUS9615354	9/1996	International				
	38	JP 63-14830	1/1988	Japan			Abstract	
	39	JP 63-140904	6/1988	Japan			X	
	40	JP 62-85449	11/1998	Japan			Abstract	
	41	WO 00/00874	1/2000	WIPO				
	42	WO 00/00873	1/2000	WIPO				
	43	WO 00/02037	1/2000	WIPO				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	44	"Requirements for Future Surface Inspection Equipment for Bare Silicon Surfaces," P. Wagner et al., Wacker-Chemitronic GmbH, Burghausen, Germany, W. Baylies, BayTech Group, Weston Massachusetts						
	45	"The Importance of Media Refractive Index in Evaluating Liquid and Surface Microcontamination Measurements," R. Knollenberg et al., <i>The Journal of Environment Sciences</i> , Mar./Apr. 1987						
	46	"Surface Inspection System for Estimation of Wafer," Y. Yatsugake et al., <i>Hitachi Engineering Technical Report</i> , Vol. 11, January 1996, pp. 21-26 (with translation)						
	47	Figure, Hitachi Electronics Engineering Co., Ltd., presented by Etsuro Morita of Mitsubishi Materials Silicon Corp. in a presentation entitled "Exploration of COP and COP Defect Crystal Originated 'Particles'." at the 6 th International Workshop on 300 mm wafers on 12/5/96 in Makuhari, Japan						
	48	"Notification of Transmittal of the International Search Report or the Declaration" corresponding to PCT/US03/28593, filed 10 September 2003, 6 pages						
Examiner			Date Considered					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								